	微纳米加工技术与量子器件	
	82305100 f hyang@red. semi . ac. cn	
	LD LED HEMT RTD	
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When do we start planning for next wafer size transition?

















































Microwave Plasma Batch System 300 Damage-free Resist Ashing and Wafer Cleaning for Semiconductor and Microel ectronics Manufacturing

- Easy Resist Removal following High dose Implant or Dry Etching
 Lowest Cost-of-Ownership of all Asher Technologies
- High Productivity, Simple Operation
- 200 mm Wafer Capability
- Minimum footprint, Flushmount Cabinet
- Microprocessor Controller

Applications:

w М •















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RTD/HEMT Integration









HEMT and MMIC Process







SOI















































Nanomechanical measurements of a superconducting qubit

Device and measurement circuit description, and driven frequency response of the nanoresonator.

c, Thenanoresonator's amplitude (main panel) and phase (upper inset) versus excitation frequency, v, for nCPB biased on and off a charge degeneracy and EJ/h<10 GHz. The solid black lines each denote a fit to a harmonic oscillator response. Lower inset: magnitude of the nanoresonator frequency shift, |DvNR/2p| (black circles) as a function ofV2 NRfor EJ/h<11–12 GHzandVCPB biased at a charge degeneracy. The solid blue line is a fit to |DvNR/2p| 5AV2 NR, where A is a proportionality constant.



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